

10A, 600V N-CHANNEL MOSFET

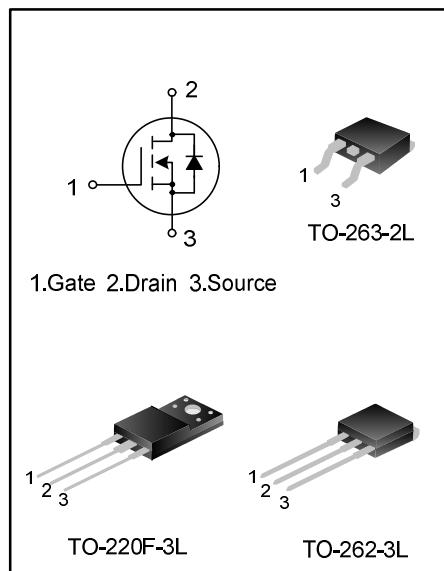
GENERAL DESCRIPTION

SVF10N60F/S/K is an N-channel enhancement mode power MOS field effect transistor which is produced using Silan proprietary F-Cell™ structure VDMOS technology. The improved process and cell structure have been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are widely used in AC-DC power supplies, DC-DC converters and H-bridge PWM motor drivers.

FEATURES

- 10A,600V, $R_{DS(on)(typ.)}=0.75\Omega @ V_{GS}=10V$
- Low gate charge
- Low Crss
- Fast switching
- Improved dv/dt capability



ORDERING INFORMATION

Part No.	Package	Marking	Hazardous Substance Control	Packing
SVF10N60F	TO-220F-3L	SVF10N60F	Pb free	Tube
SVF10N60S	TO-263-2L	SVF10N60S	Halogen free	Tube
SVF10N60STR	TO-263-2L	SVF10N60S	Halogen free	Tape&Reel
SVF10N60K	TO-262-3L	SVF10N60K	Pb free	Tube



ABSOLUTE MAXIMUM RATINGS (T_c=25°C unless otherwise noted)

Characteristics	Symbol	Ratings			Unit
		SVF10N60F	SVF10N60S	SVF10N60K	
Drain-Source Voltage	V _{DS}	600			V
Gate-Source Voltage	V _{GS}	±30			V
Drain Current	T _c = 25°C	I _D	10		A
	T _c = 100°C		6.3		
Drain Current Pulsed	I _{DM}	40			A
Power Dissipation(T _c =25°C) -Derate above 25°C	P _D	50	150	148	W
		0.4	1.20	1.18	W/°C
Single Pulsed Avalanche Energy (Note 1)	E _{AS}	654			mJ
Operation Junction Temperature Range	T _J	-55~+150			°C
Storage Temperature Range	T _{stg}	-55~+150			°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	Ratings			Unit
		SVF10N60F	SVF10N60S	SVF10N60K	
Thermal Resistance, Junction-to-Case	R _{θJC}	2.5	0.83	0.84	°C/W
Thermal Resistance, Junction-to-Ambient	R _{θJA}	62.5	62.5	62.5	°C/W



ELECTRICAL CHARACTERISTICS ($T_c=25^\circ\text{C}$ unless otherwise noted)

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Drain -Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	600	--	--	V
Drain-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=600\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1.0	μA
Gate-Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 30\text{V}, V_{\text{DS}}=0\text{V}$	--	--	± 100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}}=V_{\text{DS}}, I_{\text{D}}=250\mu\text{A}$	2.0	--	4.0	V
Static Drain- Source On State Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=5.0\text{A}$	--	0.75	0.9	Ω
Input Capacitance	C_{iss}	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1.0\text{MHZ}$	--	1086	--	pF
Output Capacitance	C_{oss}		--	143	--	
Reverse Transfer Capacitance	C_{rss}		--	12.0	--	
Turn-on Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=300\text{V}, I_{\text{D}}=10\text{A}, R_{\text{G}}=25\Omega$	--	21.7	--	ns
Turn-on Rise Time	t_r		--	41.8	--	
Turn-off Delay Time	$t_{\text{d}(\text{off})}$		--	79.4	--	
Turn-off Fall Time	t_f		--	40.9	--	
Total Gate Charge	Q_g	$V_{\text{DS}}=480\text{V}, I_{\text{D}}=10\text{A}, V_{\text{GS}}=10\text{V}$	--	28.3	--	nC
Gate-Source Charge	Q_{gs}		--	6.26	--	
Gate-Drain Charge	Q_{gd}		--	13.2	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	I_s	Integral Reverse P-N Junction Diode in the MOSFET	--	--	10	A
Pulsed Source Current	I_{SM}		--	--	40	
Diode Forward Voltage	V_{SD}	$I_s=10\text{A}, V_{\text{GS}}=0\text{V}$	--	--	1.3	V
Reverse Recovery Time	T_{rr}	$I_s=10\text{A}, V_{\text{GS}}=0\text{V}, dI/dt=100\text{A}/\mu\text{s}$ (Note 2)	--	542	--	ns
Reverse Recovery Charge	Q_{rr}		--	4.18	--	μC

Notes:

1. $L=30\text{mH}, I_{\text{AS}}=6.0\text{A}, V_{\text{DD}}=100\text{V}, R_{\text{G}}=25\Omega$, starting $T_J=25^\circ\text{C}$;
2. Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$;
3. Essentially independent of operating temperature.



TYPICAL CHARACTERISTICS

Figure 1. On-Region Characteristics

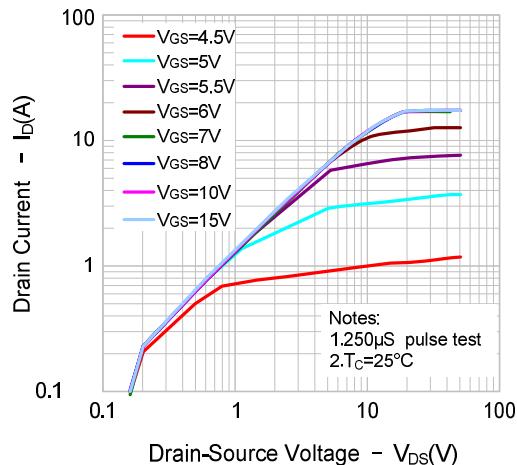


Figure 2. Transfer Characteristics

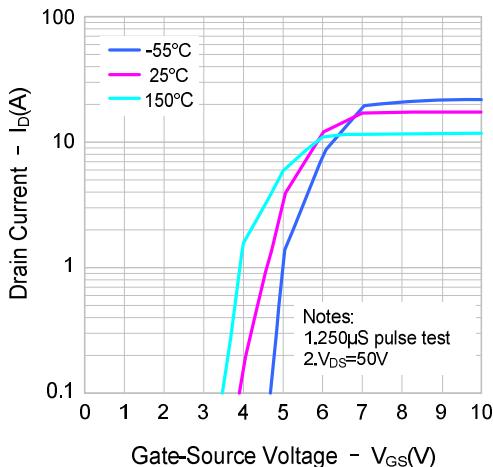


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

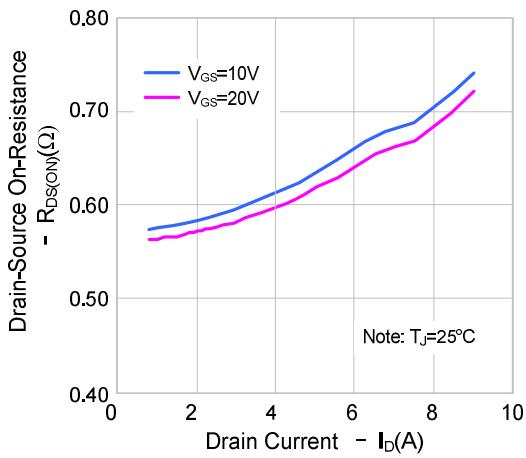


Figure 4. Body Diode Forward Voltage
Variation vs. Source Current and Temperature

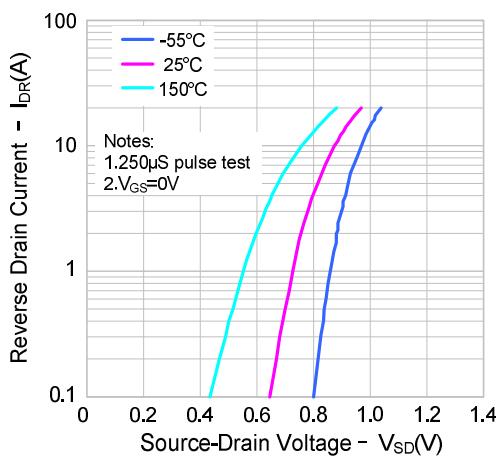


Figure 5. Capacitance Characteristics

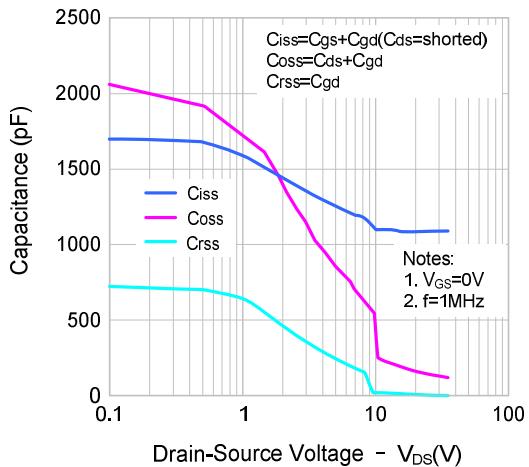
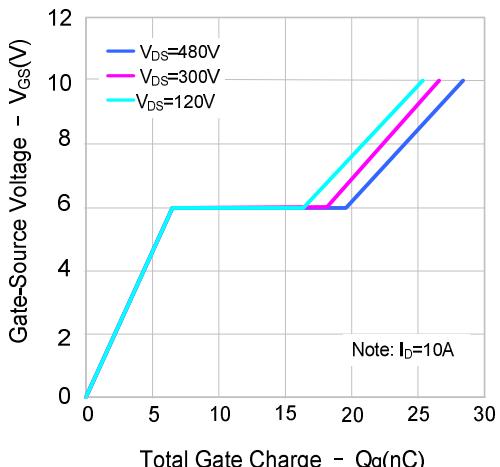


Figure 6. Gate Charge Characteristics





TYPICAL CHARACTERISTICS (continued)

Figure 7. Breakdown Voltage vs. Temperature

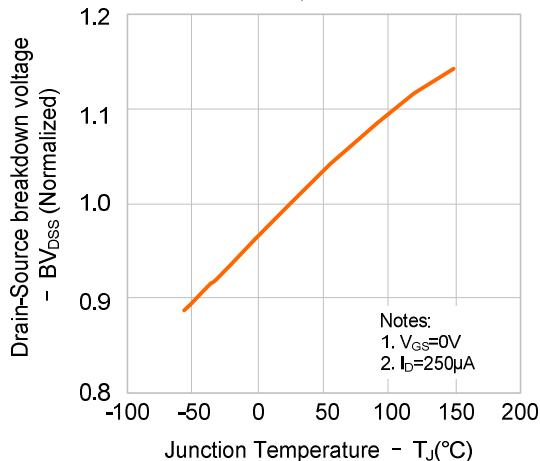


Figure 9-1. Max. Safe Operating Area(SVF10N60F)

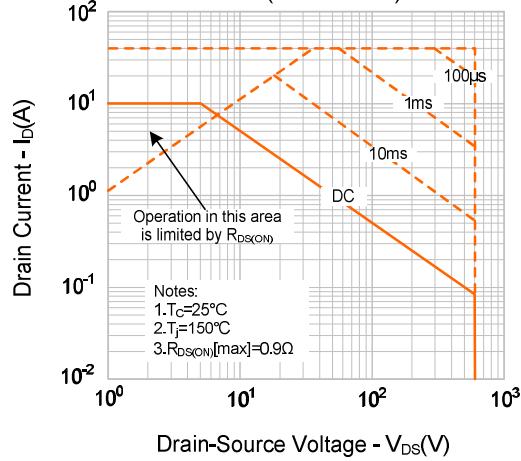


Figure 9-3. Max. Safe Operating Area(SVF10N60S)

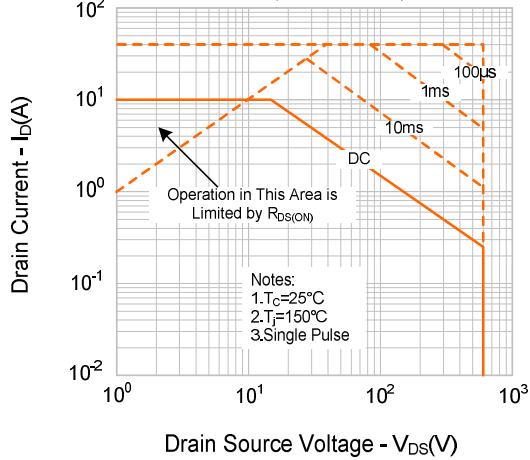


Figure 8. On-resistance Variation vs. Temperature

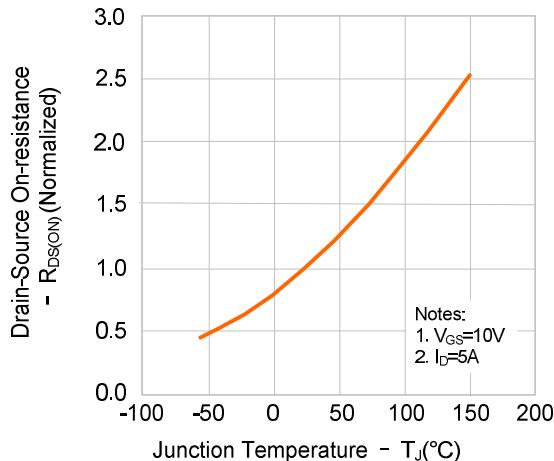


Figure 9-2. Max. Safe Operating Area(SVF10N60K)

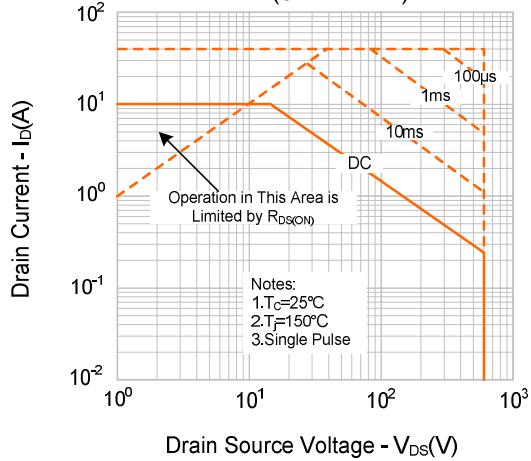
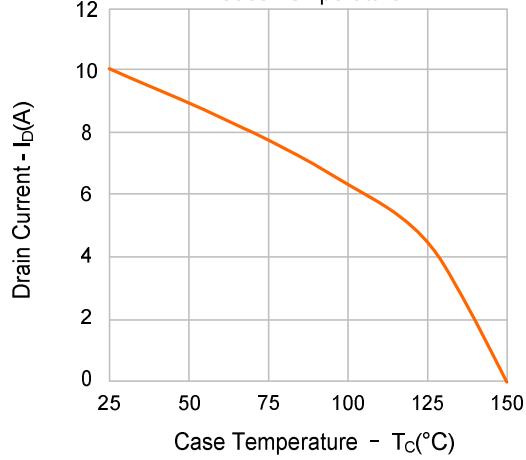
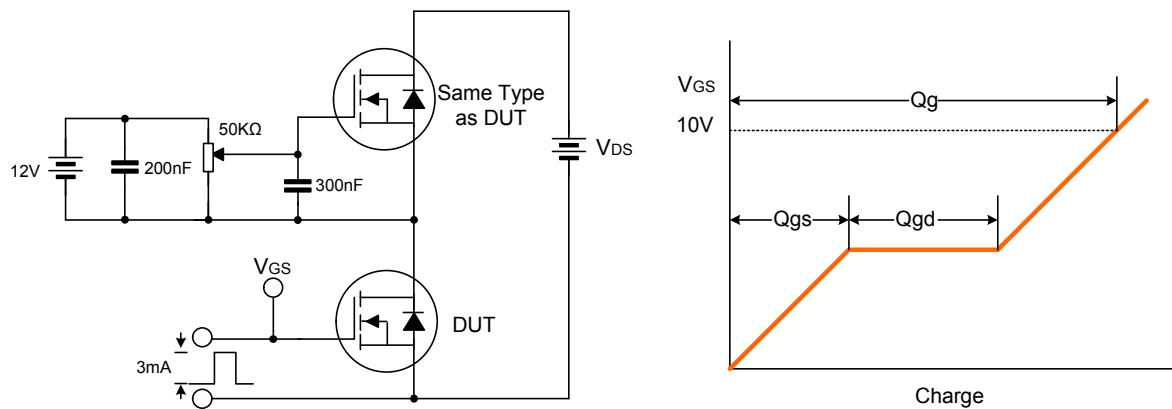


Figure 10. Maximum Drain Current vs. Case Temperature

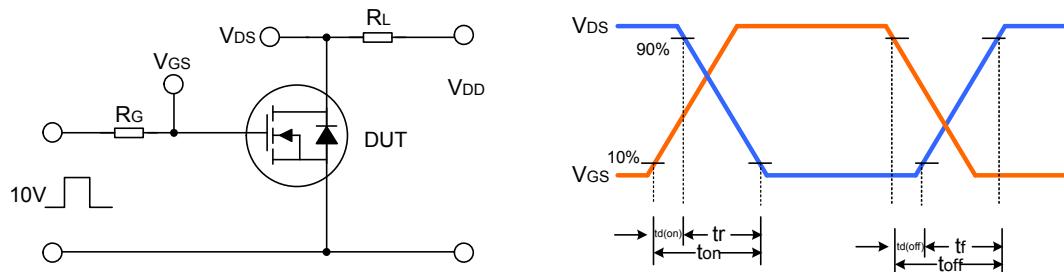


TYPICAL TEST CIRCUIT

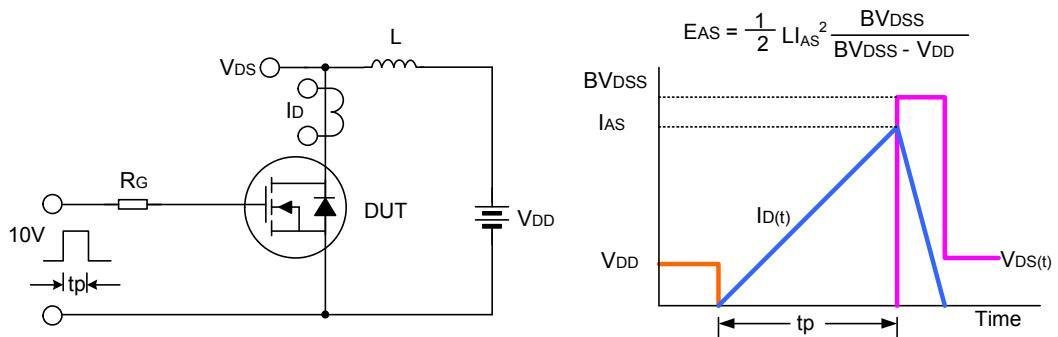
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform



Unclamped Inductive Switching Test Circuit & Waveform

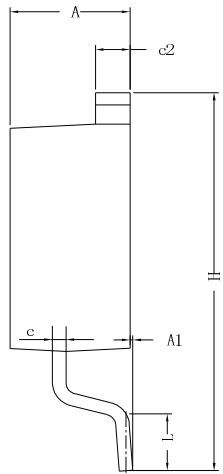
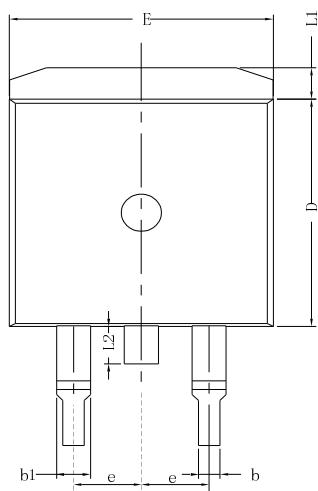




PACKAGE OUTLINE

TO-263-2L

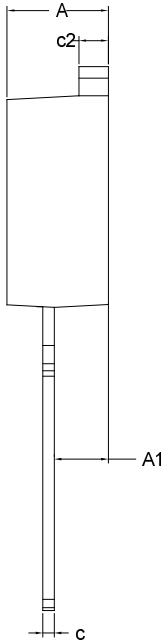
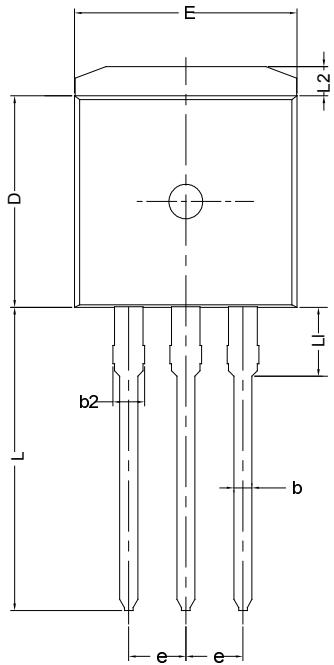
单位：毫米



SYMBOL	MIN	NOM	MAX
A	4.30	4.57	4.72
A1	0	0.10	0.25
b	0.71	0.81	0.91
c	0.30	---	0.60
c2	1.17	1.27	1.37
D	8.50	---	9.35
E	9.80	---	10.45
e		2.54 BSC	
H	14.70	---	15.75
L	2.00	2.30	2.74
L1	1.12	1.27	1.42
L2	---	---	1.75

TO-262-3L

单位：毫米

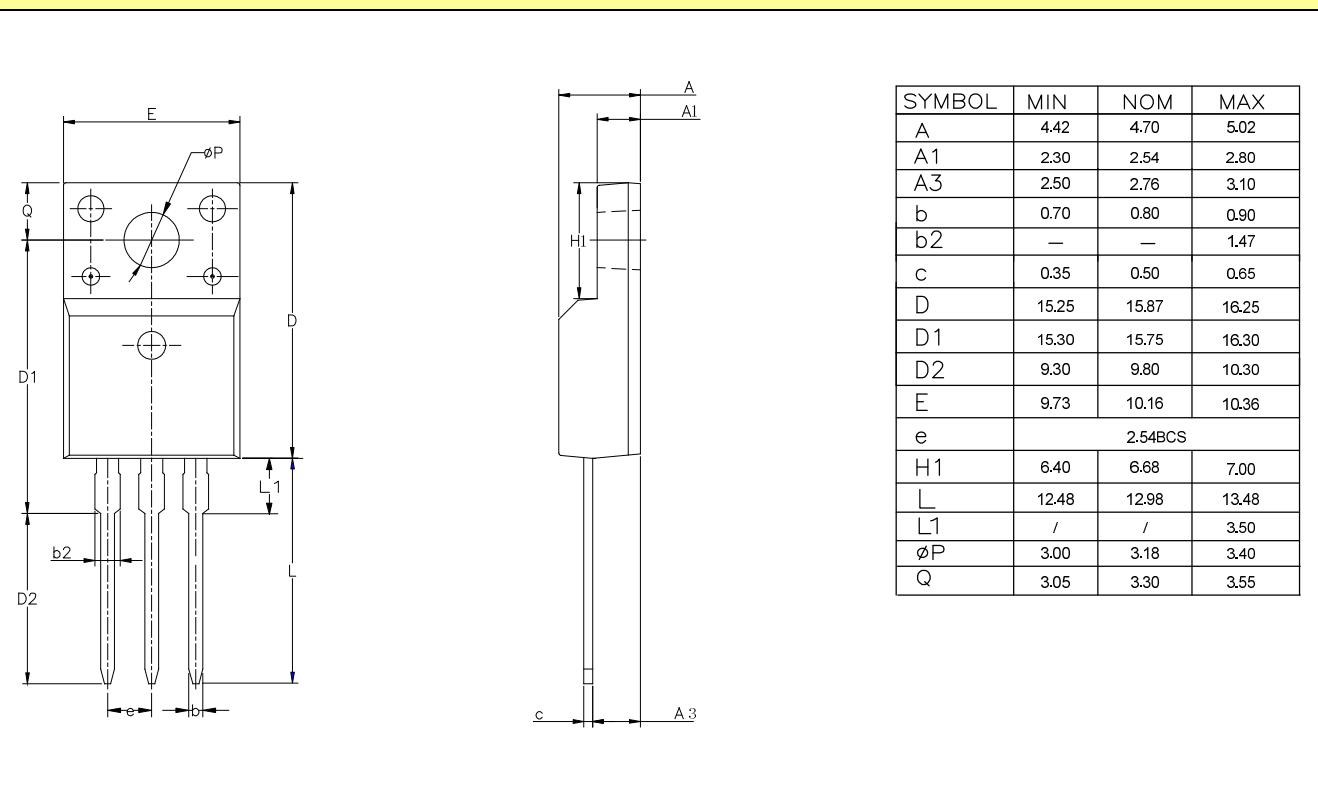


SYMBOL	MIN	NOM	MAX
A	4.30	4.50	4.70
A1	2.20	---	2.92
b	0.71	0.80	0.97
b2	1.20	---	1.50
c	0.34	---	0.76
c2	1.22	1.30	1.35
D	8.38	---	9.30
E	9.80	10.16	10.54
e		2.54 BSC	
L	12.80	---	14.10
L1	2.80	3.30	4.06
L2	1.12	---	1.42

PACKAGE OUTLINE

TO-220F-3L

UNIT: mm



Disclaimer :

- Silan reserves the right to make changes to the information herein for the improvement of the design and performance without prior notice! Customers should obtain the latest relevant information before placing orders and should verify that such information is complete and current.
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- Silan will supply the best possible product for customers!

Part No.: **SVF10N60F/S/K** Document Type: **Datasheet**
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Rev.: **2.4**

Revision History:

1. Delete the package outline of TO-220-3L
-

Rev.: **2.3**

Revision History:

1. Modify the Electrical characteristics
-

Rev.: **2.2**

Revision History:

1. Modify the general description
 2. Modify the ordering information
 3. Modify the package outline of TO-263-2L and TO-262-3L
-

Rev.: **2.1**

Revision History:

1. Modify the ordering information
 2. Modify the package information of TO-220-3L
-

Rev.: **2.0**

Revision History:

1. Modify the package information
-

Rev.: **1.9**

Revision History:

1. Modify the thermal characteristics
-

Rev.: **1.8**

Revision History:

1. Modify the ordering information
-

Rev.: **1.7**

Revision History:

1. Change the schematic diagram of MOS
-

Rev.: **1.6**

Revision History:

1. Modify "PACKAGE OUTLINE"
-

Rev.: **1.5**

Revision History:

1. Modify the values of T_{rr} and Q_{rr}
-

Rev.: **1.4**

Revision History:

1. Add the halogen free information of SVF10N60F
-

Rev.: **1.3**

Revision History:



1. Add the package of TO-262-3L

Rev.: 1.2

Revision History:

1. Modify "PACKAGE OUTLINE"

Rev.: 1.1

Revision History:

1. Add the package of TO-263-2L

Rev.: 1.0

Revision History:

1. Original
